

RELIABILITY MONITOR

DS1232L JAN '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1232	C2-L	0051	DK038265AAC	8	SOIC	150x1.4	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 0.8 µm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26435	INFANT LIFE	125C, 7.0 VOLTS	233	48	HOUR	0
26436	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	76	1000	HOUR	0
TOTAL:			30	FAIL RATE (Fits):		0
TOTAL:			DEVICE HRS: 3.05E+07			
26432	ULTRASOUND	J-STD-020	4			0
TOTAL:						
26433	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:						
26434	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						
26437	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						
26438	HAST	130C, 85%R.H.,5.5V	77	100	HOUR	2
TOTAL:						

PROJECT NO: 16721

RELIABILITY MONITOR

DS1232L JAN '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1232	C2-L	0051	DK038265AAC	8	SOIC	150x1.4	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26439	AUTOCLAVE	121C STEAM, UNBIASED	39	96	HOUR	0
TOTAL:						0

JOB NO	FAILURE MODE	FAILURE MECHANISM / CORRECTION
26438	POWER FAIL	IN PROCESS

RELIABILITY MONITOR

DS1232L APR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1232	C2-L	0105	DE045054ABB	8	SOIC	150x1.4	OSEP
PROCESS Single Poly, Single Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26864	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
TOTAL:			101	FAIL RATE (Fits):		0
				DEVICE HRS: 9.04E+06		
26861	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
26862	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:						0
26863	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0
26865	TEMP CYCLE	-55C TO 125C	40	300	CYCL	1
			39	1000	CYCL	0
TOTAL:						1
26866	HAST	130C, 85%R.H.,5.5V	77	88	HOUR	0
TOTAL:						0
26867	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

PROJECT NO: 17981

RELIABILITY MONITOR

DS1232L APR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1232	C2-L	0105	DE045054ABB	8	SOIC	150x1.4	OSEP
PROCESS Single Poly, Single Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

NO OF

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
JOB NO	FAILURE MODE	FAILURE MECHANISM / CORRECTION				
26865	OPENS	IN PROCESS				

RELIABILITY MONITOR

DS1232L JUL '01 MONITOR

DEVICE	REVISIO	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1232	C2-L	0105	DK046225ABB	8	SOIC	150x1.4	ATP (Anam, PI)

JOB_NO	DESCRIPTION	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
27337	STORAGE LIFE	125C	241	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	241	168	HOUR	
	CONVECTION REFLOW	235C	241	3	PASS	0
		TOTAL:				0
27338	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
27340	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
		TOTAL:				0
27342	AUTOCLAVE	121C STEAM, UNBIASED	39	96	HOUR	0
		TOTAL:				0

PROJECT NO: 18776

RELIABILITY MONITOR

DS1233Z-10 APR '01 MONITOR

DEVICE	REVISIO	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1233	A5	0101	DA048537AF	3	SOT223	140x1.7	Fastech

JOB_NO	DESCRIPTION	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26868	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
26869	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0

PROJECT NO: 17982

RELIABILITY MONITOR

DS1267-100 FEB '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1267	A2	9930	DK904472ADF	20	TSSOP	4.4x0.9	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 1.2 µm Implanted Poly 1							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25175	INFANT LIFE	125C, 6.0 V, -4.0V	226	48	HOUR	0
25176	HIGH VOLTAGE LIFE	125C, 6.0 V, -4.0V	77	336	HOUR	0
		125C, 6.0 V, -4.0V	77	1000	HOUR	0
TOTAL:			90	FAIL RATE (Fits): DEVICE HRS: 1.02E+07		0
25172	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
25173	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:						0
25174	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0
25177	TEMP CYCLE	-55C TO 125C	36	300	CYCL	0
			36	1000	CYCL	0
TOTAL:						0
25178	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0

PROJECT NO: 14260

RELIABILITY MONITOR

DS1267-100 FEB '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1267	A2	9930	DK904472ADF	20	TSSOP	4.4x0.9	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 1.2 μ m Implanted Poly 1							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
		TOTAL:				0
25179	AUTOCLAVE	121C STEAM, UNBIASED	36	96	HOUR	0
		TOTAL:				0

RELIABILITY MONITOR

DS1267-010 FEB '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1267	A1	0102	DM039441ABC	20	TSSOP	4.4x0.9	Carsem S
PROCESS Single Poly, Single Metal 1.2 µm Implanted Poly 1							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26571	INFANT LIFE	125C, 6.0 V, -4.0V	234	48	HOUR	0
26572	HIGH VOLTAGE LIFE	125C, 6.0 V, -4.0V	77	336	HOUR	0
		125C, 6.0 V, -4.0V	76	1000	HOUR	0
TOTAL:			83	FAIL RATE (Fits): DEVICE HRS: 1.11E+07		0
26568	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
26569	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:						0
26570	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0
26573	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
26574	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0

PROJECT NO: 17061

RELIABILITY MONITOR

DS1267-010 FEB '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1267	A1	0102	DM039441ABC	20	TSSOP	4.4x0.9	Carsem S
PROCESS Single Poly, Single Metal 1.2 μ m Implanted Poly 1							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
		TOTAL:				0
26575	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	0
		TOTAL:				0

PROJECT NO: 17061

RELIABILITY MONITOR

DS1267-010 MAY '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1267	A1	0104	DK043419AAB	20	TSSOP	4.4x0.9	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 1.2 µm Implanted Poly 1							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26979	HIGH VOLTAGE LIFE	125C, 6.0 V, -4.0V	75	336	HOUR	0
		TOTAL:	283	DEVICE HRS:	3.24E+06	0
26976	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
26977	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
26980	TEMP CYCLE	-55C TO 125C	35	300	CYCL	0
		TOTAL:				0
26981	BIASED MOISTURE	85/85, 5.5 VOLTS	75	274	HOUR	0
		TOTAL:				0
26982	AUTOCLAVE	121C STEAM, UNBIASED	34	96	HOUR	0
		TOTAL:				0

PROJECT NO: 18202

RELIABILITY MONITOR

DS1302 MAR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1302	A3	0105	DH036622AB	8	PDIP	300	CPS (ChipPac, China)
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26749	INFANT LIFE	125C, 6.0 VOLTS	234	48	HOUR	0
26750	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	1000	HOUR	0
TOTAL:			114	DEVICE HRS: 8.01E+06		0
26751	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
26752	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
26753	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

PROJECT NO: 17761

RELIABILITY MONITOR

DS1620 JUN '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1620	D1	0109	DH046190AAI	8	SOIC	208x1.9	CPS (ChipPac, China)
PROCESS Single Poly, Single Metal 0.8 μm E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS	
27093	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0	
		125C, 7.0 VOLTS	77	1000	HOUR	0	
		TOTAL:	FAIL RATE (Fits): 34	DEVICE HRS: 2.69E+07		0	
27090	ULTRASOUND	J-STD-020	4				
		TOTAL:					
27091	STORAGE LIFE	125C	241	24	HOUR		
		MOISTURE SOAK	85C/85% R.H.	241	168	HOUR	
		CONVECTION REFLOW	235C	241	3	PASS	0
		TOTAL:				0	
27092	PRECONDITION U/S	J-STD-020	4			0	
		TOTAL:				0	
27094	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0	
			40	1000	CYCL	0	
		TOTAL:				0	
27095	BIASED MOISTURE	85/85, 5.5 VOLTS	70	274	HOUR	1	
		TOTAL:				1	
27096	WRITE CYCLE STRESS	85 C, 7.0 VOLTS	50	50	KCYC	0	

PROJECT NO: 18427

RELIABILITY MONITOR

DS1620 JUN '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1620	D1	0109	DH046190AAI	8	SOIC	208x1.9	CPS (ChipPac, China
PROCESS Single Poly, Single Metal 0.8 μm E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

NO OF

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	FAILS
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TOTAL:	0
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JOB NO	FAILURE MODE	FAILURE MECHANISM / CORRECTION
27095	OPENS	IN PROCESS

RELIABILITY MONITOR

DS1803-010 FEB '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	0007	DE946274AAA	16	SOIC	150x1.4	OSEP
PROCESS Single Poly, Double Metal 0.8 µm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25191	INFANT LIFE	125C, 7.0 VOLTS	226	48	HOUR	0
25192	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	75	336	HOUR	0
		125C, 7.0 VOLTS	62	1000	HOUR	0
TOTAL:			38	FAIL RATE (Fits): DEVICE HRS: 2.43E+07		0
25188	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
25189	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:						0
25190	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0
25193	TEMP CYCLE	-55C TO 125C	35	300	CYCL	0
			27	1000	CYCL	0
TOTAL:						0
25194	BIASED MOISTURE	85/85, 5.5 VOLTS	68	274	HOUR	0
			57	959	HOUR	0

PROJECT NO: 14167

RELIABILITY MONITOR

DS1803-010 FEB '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	0007	DE946274AAA	16	SOIC	150x1.4	OSEP
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
		TOTAL:				0
25195	AUTOCLAVE	121C STEAM, UNBIASED	35	96	HOUR	0
		TOTAL:				0

PROJECT NO: 14167

RELIABILITY MONITOR

DS1803-010 MAY '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	0013	DE951193AAF	16	SOIC	150x1.4	OSEP
PROCESS Single Poly, Double Metal 0.8 μ m Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25438	INFANT LIFE	125C, 7.0 VOLTS	227	48	HOUR	0
25439	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	76	336	HOUR	0
		125C, 7.0 VOLTS	65	1000	HOUR	0
		TOTAL:	35	FAIL RATE (Fits): DEVICE HRS: 2.59E+07		0
25435	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
25436	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
25437	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
25440	TEMP CYCLE	-55C TO 125C	35	300	CYCL	0
			20	1000	CYCL	0
		TOTAL:				0
25441	BIASED MOISTURE	85/85, 5.5 VOLTS	64	274	HOUR	0
		TOTAL:				0

PROJECT NO: 15292

RELIABILITY MONITOR

DS1803-010 MAY '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	0013	DE951193AAF	16	SOIC	150x1.4	OSEP
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25442	AUTOCLAVE	121C STEAM, UNBIASED	35	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS1803-010 AUG '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	0034	DE023435AAB	16	SOIC	150x1.4	OSEP
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25925	INFANT LIFE	125C, 7.0 VOLTS	221	48	HOUR	1
25926	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
TOTAL:			67	FAIL RATE (Fits):		3.01E+07
25922	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
25923	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:						0
25924	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0
25927	TEMP CYCLE	-55C TO 125C	35	300	CYCL	0
			35	1000	CYCL	0
TOTAL:						0
25928	BIASED MOISTURE	85/85, 5.5 VOLTS	64	274	HOUR	1
			63	959	HOUR	0

PROJECT NO: 16359

RELIABILITY MONITOR

DS1803-010 AUG '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	0034	DE023435AAB	16	SOIC	150x1.4	OSEP
PROCESS Single Poly, Double Metal 0.8 μ m Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						1
25929	AUTOCLAVE	121C STEAM, UNBIASED	30	96	HOUR	0
TOTAL:						0
JOB NO	FAILURE MODE	FAILURE MECHANISM / CORRECTION				
25925	IIH	IN PROCESS				
25928	LO	IN PROCESS				

PROJECT NO: 16359

RELIABILITY MONITOR

DS1803-010 FEB '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	0105	DE047362AAB	16	SOIC	150x1.4	OSEP
PROCESS Single Poly, Double Metal 0.8 µm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26609	INFANT LIFE	125C, 7.0 VOLTS	232	48	HOUR	0
TOTAL:			244	FAIL RATE (Fits):		0
			DEVICE HRS: 3.76E+06			
26606	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
26607	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:						0
26608	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0
26611	TEMP CYCLE	-55C TO 125C	40	300	CYCL	6
TOTAL:						6

JOB NO	FAILURE MODE	FAILURE MECHANISM / CORRECTION
26611	3 LO	IN PROCESS

PROJECT NO: 17281

RELIABILITY MONITOR

DS1869 JUN '00 MONITOR						
DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH ASSEMBLY SITE
DS1869	A3	0017	DH833210AAB	8	SOIC	208x1.9 CPS (ChipPac, China)
PROCESS	Single Poly, Single Metal 1.2 µm E2PROM process					

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25543	INFANT LIFE	125C, 7.0 VOLTS	236	48	HOUR	0
25544	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	76	336	HOUR	0
		125C, 7.0 VOLTS	75	1000	HOUR	0
		TOTAL:	30	FAIL RATE (Fits): DEVICE HRS: 3.01E+07		0
25540	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
25541	STORAGE LIFE	125C	241	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	241	168	HOUR	
	CONVECTION REFLOW	235C	241	3	PASS	0
		TOTAL:				0
25542	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
25545	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
25546	BIASED MOISTURE	85/85, 5.5 VOLTS	70	274	HOUR	0
			69	959	HOUR	0

PROJECT NO: 14164

RELIABILITY MONITOR

DS1869 JUN '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1869	A3	0017	DH833210AAB	8	SOIC	208x1.9	CPS (ChipPac, China)
PROCESS Single Poly, Single Metal 1.2 μ m E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β :

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0
25547	WRITE CYCLE STRESS	85 C, 7.0 VOLTS	48	25	KCYC	0
	STORAGE LIFE	150C	46	336	HOUR	0
			46	1000	HOUR	0
TOTAL:						0

PROJECT NO: 14164

RELIABILITY MONITOR

DS2108 FEB '01 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2108	B7	0051	DN041061AAE	24	SOIC	300x2.3	ATK (Anam, K)
PROCESS Single Poly, Single Metal 5.0 µm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26579	INFANT LIFE	125C, 6.0 VOLTS	234	48	HOUR	0
26580	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	77	1000	HOUR	0
TOTAL:			81	FAIL RATE (Fits): DEVICE HRS: 1.13E+07		0
26576	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
26577	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	238	144	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:						0
26578	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0
26581	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
26582	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			75	959	HOUR	1

PROJECT NO: 17081

RELIABILITY MONITOR

DS2108 FEB '01 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2108	B7	0051	DN041061AAE	24	SOIC	300x2.3	ATK (Anam, K)
PROCESS Single Poly, Single Metal 5.0 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						1
26583	AUTOCLAVE	121C STEAM, UNBIASED	39	96	HOUR	0
TOTAL:						0
JOB NO	FAILURE MODE	FAILURE MECHANISM / CORRECTION				
26582	IIL R9 _10.868 UA	IN PROCESS				

PROJECT NO: 17081

RELIABILITY MONITOR

DS2108 MAY '01 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2108	B7	0111	DK101048AAC	24	SOIC	300x2.3	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 5.0 µm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26986	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		TOTAL:	276	DEVICE HRS: 3.32E+06		0
26983	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
26984	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	238	144	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
26985	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
26987	TEMP CYCLE	-55C TO 125C	40	300	CYCL	1
		TOTAL:				1
26988	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
		TOTAL:				0
26989	AUTOCLAVE	121C STEAM, UNBIASED	40	96	HOUR	1
		TOTAL:				1

PROJECT NO: 18203

RELIABILITY MONITOR

DS2108 MAY '01 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2108	B7	0111	DK101048AAC	24	SOIC	300x2.3	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 5.0 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

NO OF

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	FAILS
JOB NO	FAILURE MODE	FAILURE MECHANISM / CORRECTION				
26987	RBOT 1	IN PROCESS				
26989	IIL R1_8	IN PROCESS				

PROJECT NO: 18203

RELIABILITY MONITOR

DS2118M JUN '01 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2118M	B1	0117	DN101149AAD	36	SSOP	7.5x2.4	ATK (Anam, K)
PROCESS Single Poly, Single Metal 0.6 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
27114	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	77	1000	HOUR	0
		125C, 6.0 VOLTS	77	1000	HOUR	0
		TOTAL:	FAIL RATE (Fits): 46	DEVICE HRS: 1.98E+07		
27111	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
27112	STORAGE LIFE MOISTURE SOAK CONVECTION REFLOW	125C	238	24	HOUR	
		60C/60% R.H.	238	40	HOUR	
		235C	238	3	PASS	0
		TOTAL:				0
27113	PRECONDITION U/S	J-STD-020	4			
		TOTAL:				
27115	TEMP CYCLE	-55C TO 125C	80	300	CYCL	0
			80	1000	CYCL	0
		TOTAL:				0
27116	AUTOCLAVE	121C STEAM, UNBIASED	77	96	HOUR	0

PROJECT NO: 18663

RELIABILITY MONITOR

DS2118M JUN '01 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2118M	B1	0117	DN101149AAD	36	SSOP	7.5x2.4	ATK (Anam, K)
PROCESS Single Poly, Single Metal 0.6 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0

PROJECT NO: 18663

RELIABILITY MONITOR

DS21352 JUN '01 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21352	A4	0103	DN033071AAA	100	LQFP	14x14x	ATP (Anam, PI)
PROCESS Double Poly, Double Met 0.6 µm Capacitor							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
27346	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
TOTAL:			276	FAIL RATE (Fits): DEVICE HRS: 3.32E+06		0
27343	ULTRASOUND	J-STD-020	4			
TOTAL:						
27344	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	60C/60% R.H.	238	40	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	5
TOTAL:			5			
27345	PRECONDITION U/S	J-STD-020	4			
TOTAL:						
27347	TEMP CYCLE	-55C TO 125C	80	300	CYCL	0
TOTAL:			0			
27348	HAST, NO BIAS	130C, 85% R.H.	62	200	HOUR	0
TOTAL:			0			

PROJECT NO: 18661

RELIABILITY MONITOR

DS21352 JUN '01 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21352	A4	0103	DN033071AAA	100	LQFP	14x14x	ATP (Anam, PI)
PROCESS Double Poly, Double Met 0.6 μm Capacitor							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

NO OF

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	FAILS
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JOB NO	FAILURE MODE	FAILURE MECHANISM / CORRECTION
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27344	BIN 4	IN PROCESS
27344	BIN 2	IN PROCESS
27344	BIN 3	IN PROCESS

PROJECT NO: 18661

RELIABILITY MONITOR

DS21352 MAR '01 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21352	A4	0103	DN033071AAA	100	LQFP	14x14x	ATK (Anam, K)
PROCESS Double Poly, Double Met 0.6 μm Capacitor							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26769	INFANT LIFE	125C, 6.0 VOLTS	224	48	HOUR	6
26770	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	76	1000	HOUR	0
TOTAL:			672	FAIL RATE (Fits): DEVICE HRS: 1.09E+07		6
26766	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
26767	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	238	240	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	4
TOTAL:						4
26768	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0
26771	TEMP CYCLE	-55C TO 125C	77	300	CYCL	0
			76	1000	CYCL	0
TOTAL:						0
26772	HAST, NO BIAS	130C, 85% R.H.	61	200	HOUR	0
TOTAL:						0

PROJECT NO: 17764

RELIABILITY MONITOR

DS21352 MAR '01 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21352	A4	0103	DN033071AAA	100	LQFP	14x14x	ATK (Anam, K)
PROCESS Double Poly, Double Met 0.6 μm Capacitor							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

NO OF

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	FAILS
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JOB NO	FAILURE MODE	FAILURE MECHANISM / CORRECTION			
26767	BIN 4	IN PROCESS			
26769	BASICB _ESF 20	IN PROCESS			

PROJECT NO: 17764

RELIABILITY MONITOR

DS2154 MAR '01 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2154	A2	0106	DN040708AA-1	100	LQFP	14x14x	ATK (Anam, K)
PROCESS Double Poly, Double Met 0.8 μm Capacitor							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26762	INFANT LIFE	125C, 6.0 VOLTS	232	48	HOUR	2
26763	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	77	1000	HOUR	0
TOTAL:			279	FAIL RATE (Fits): DEVICE HRS: 1.11E+07		2
26759	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
26760	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	238	240	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:						0
26761	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0
26764	TEMP CYCLE	-55C TO 125C	80	300	CYCL	0
			80	1000	CYCL	0
TOTAL:						0
26765	HAST, NO BIAS	130C, 85% R.H.	68	200	HOUR	0
TOTAL:						0

PROJECT NO: 17763

RELIABILITY MONITOR

DS2154 MAR '01 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2154	A2	0106	DN040708AA-1	100	LQFP	14x14x	ATK (Anam, K)
PROCESS Double Poly, Double Met 0.8 μm Capacitor							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

NO OF

FAILS

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
JOB NO	FAILURE MODE	FAILURE MECHANISM / CORRECTION				
26762	SIG_CAPB	IN PROCESS				
26762	CONTB	IN PROCESS				

PROJECT NO: 17763

RELIABILITY MONITOR

DS2154 JUN '01 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2154	A2	0107	DC040702AA-1	100	LQFP	14x14x	Stats
PROCESS Double Poly, Double Met 0.8 µm Capacitor							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
27101	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
TOTAL:			279	FAIL RATE (Fits):		0
			DEVICE HRS: 3.28E+06			
27098	ULTRASOUND	J-STD-020	4			
TOTAL:						
27099	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	60C/60% R.H.	238	40	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:			0			
27100	PRECONDITION U/S	J-STD-020	4			
TOTAL:						
27102	TEMP CYCLE	-55C TO 125C	80	300	CYCL	0
TOTAL:			0			
27103	HAST, NO BIAS	130C, 85% R.H.	76	200	HOUR	0
TOTAL:			0			

PROJECT NO: 18642

RELIABILITY MONITOR

DS2154 SEP '01 MONITOR, D.P.

DEVICE	REVISIO	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2154	A2	0125	DN104641AA-1	100	LQFP	14x14x	ATK (Anam, K)

JOB_NO	DESCRIPTION	CONDITION	QUANTITY	READPOINT UNITS	NO OF FAILS
27838	ULTRASOUND	J-STD-020	4		0
		TOTAL:			0
27840	PRECONDITION U/S	J-STD-020	4		0
		TOTAL:			0

PROJECT NO: 19201

RELIABILITY MONITOR

DS2175 JAN '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2175	D1	0046	DE033119AAB	16	SOIC	300x2.3	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 2.0 µm Pfield							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26422	INFANT LIFE	125C, 7.0 VOLTS	233	48	HOUR	0
26423	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
TOTAL:			71	DEVICE HRS: 1.29E+07		0
26419	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
26420	TEMP CYCLE	-55C TO 125C	238	10	CYCL	
	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:						0
26421	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0
26424	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
26425	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
TOTAL:						0

PROJECT NO: 16724

RELIABILITY MONITOR

DS2175 JAN '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2175	D1	0046	DE033119AAB	16	SOIC	300x2.3	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 2.0 μm Pfield							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26426	AUTOCLAVE	121C STEAM, UNBIASED	39	96	HOUR	0
TOTAL:						0

PROJECT NO: 16724

RELIABILITY MONITOR

DS2175 APR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2175	D1	0050	DK036683ABD	16	SOIC	300x2.3	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 2.0 µm Pfield							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26883	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
TOTAL:			101	FAIL RATE (Fits):		0
				DEVICE HRS: 9.04E+06		
26880	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
26881	TEMP CYCLE	-55C TO 125C	238	10	CYCL	
	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:						0
26882	PRECONDITION U/S	J-STD-020	4			
TOTAL:						
26884	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
TOTAL:						0

PROJECT NO: 18002

RELIABILITY MONITOR

DS21S07 FEB '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS PACKAGE	WIDTH ASSEMBLY SITE
DS21S07	C1-A	0047	DM035532AFD 20	TSSOP	4.4x0.9 Carsem S
PROCESS Single Poly, Single Metal 0.8 µm Negative zero tempco poly					

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26588	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	8
		TOTAL:			FAIL RATE (Fits): 377	DEVICE HRS: 2.50E+07
26584	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
26585	STORAGE LIFE MOISTURE SOAK CONVECTION REFLOW	125C	238	24	HOUR	
		85C/85% R.H.	238	168	HOUR	
		235C	238	3	PASS	0
		TOTAL:				0
26586	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
26589	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
26590	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
		TOTAL:				0

PROJECT NO: 17101

RELIABILITY MONITOR

DS21S07 FEB '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21S07	C1-A	0047	DM035532AFD	20	TSSOP	4.4x0.9	Carsem S
PROCESS Single Poly, Single Metal 0.8 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26591	AUTOCLAVE	121C STEAM, UNBIASED	36	96	HOUR	0
TOTAL:						0

JOB NO	FAILURE MODE	FAILURE MECHANISM / CORRECTION
26588	CONTINUITY	IN PROCESS

PROJECT NO: 17101

RELIABILITY MONITOR

DS2502 JUL '01 MONITOR

DEVICE	REVISIO	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2502	C4	0125	DE052527ACA	6	TSOC	150x1.2	OSEP

JOB_NO	DESCRIPTION	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
27372	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
27373	STORAGE LIFE	125C	151	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	151	168	HOUR	
	CONVECTION REFLOW	235C	151	3	PASS	0
		TOTAL:				0
27374	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
27375	TEMP CYCLE	-55C TO 125C	77	300	CYCL	0
		TOTAL:				0
27376	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	70	96	HOUR	0
		TOTAL:				0

PROJECT NO: 18780

RELIABILITY MONITOR

DS5002 JAN '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS5002	C5	0047	DN028766AAD	80	MQFP	14x20x	ATK (Anam, K)
PROCESS Single Poly, Single Metal 0.6 µm Buried contacts w/silicided poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26508	INFANT LIFE	125C, 6.0 VOLTS	198	48	HOUR	0
26509	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	77	1000	HOUR	0
TOTAL:			83	FAIL RATE (Fits): DEVICE HRS: 1.11E+07		0
26505	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
26506	STORAGE LIFE	125C	203	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	203	144	HOUR	
	VAPOR PHASE REFLOW	220C	203	3	PASS	0
TOTAL:						0
26507	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0
26510	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
26511	BIASED MOISTURE	85/85, 5.5 VOLTS	42	274	HOUR	0
TOTAL:						0

PROJECT NO: 16727

RELIABILITY MONITOR

DS5002 JAN '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS5002	C5	0047	DN028766AAD	80	MQFP	14x20x	ATK (Anam, K)
PROCESS Single Poly, Single Metal 0.6 μm Buried contacts w/silicided poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26512	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	37	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS5002 APR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS5002	C5	0112	DN030363AAA	80	MQFP	14x20x	ATK (Anam, K)
PROCESS Single Poly, Single Metal 0.6 µm Buried contacts w/silicided poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26901	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	77	1000	HOUR	0
		TOTAL:	FAIL RATE (Fits): 94	DEVICE HRS: 9.72E+06		0
26898	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
26899	STORAGE LIFE MOISTURE SOAK VAPOR PHASE REFLOW	125C	203	24	HOUR	
		30C/60% R.H.	203	144	HOUR	
		220C	203	3	PASS	0
		TOTAL:				0
26900	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
26902	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
26903	BIASED MOISTURE	85/85, 5.5 VOLTS	42	274	HOUR	0
		TOTAL:				0
26904	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	39	96	HOUR	0

PROJECT NO: 18041

RELIABILITY MONITOR

DS5002 APR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS5002	C5	0112	DN030363AAA	80	MQFP	14x20x	ATK (Anam, K)
PROCESS Single Poly, Single Metal 0.6 μ m Buried contacts w/silicided poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0

RELIABILITY MONITOR

DS5002 JUL '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS5002	C6	0122	DN042297AAA	80	MQFP	14x20x	ATK (Anam, K)
PROCESS Single Poly, Single Metal 0.6 µm Buried contacts w/silicided poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
27364	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	80	336	HOUR	0
		TOTAL:	265	DEVICE HRS: 3.45E+06		0
27362	STORAGE LIFE	125C	206	24	HOUR	
	MOISTURE SOAK	60C/60% R.H.	206	40	HOUR	
	CONVECTION REFLOW	220C	206	3	PASS	0
		TOTAL:				0
27363	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
27365	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
		TOTAL:				0
27367	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	40	96	HOUR	0
		TOTAL:				0

PROJECT NO: 18779

RELIABILITY MONITOR

DS80C320 APR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS80C320	C5	0111	DH040746AA	40	PDIP	600	CPS (ChipPac, China)
PROCESS Single Poly, Single Metal 0.6 μm PolySilicide							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26894	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
TOTAL:			101	DEVICE HRS: 9.04E+06		0
26895	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
TOTAL:						0
26896	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
TOTAL:						0
26897	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

PROJECT NO: 18021

RELIABILITY MONITOR

DS80CH11 MAR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS80CH11	A4	0103	DN029182AAA	128	LQFP	14x20x	ATK (Anam, K)
PROCESS Single Poly, Double Metal 0.6 μm PolySilicide							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26786	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
27058	INFANT LIFE	125C, 6.0 VOLTS	235	48	HOUR	0
TOTAL:			199	FAIL RATE (Fits): DEVICE HRS: 4.60E+06		0
26782	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
26783	STORAGE LIFE	125C	239	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	239	240	HOUR	
	CONVECTION REFLOW	235C	239	3	PASS	0
TOTAL:						0
26784	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0
26787	TEMP CYCLE	-55C TO 125C	70	300	CYCL	0
TOTAL:						0
26788	BIASED MOISTURE	85/85, 5.5 VOLTS	48	274	HOUR	0
TOTAL:						0
26789	HAST, NO BIAS	130C, 85% R.H.	40	100	HOUR	0
TOTAL:						0

PROJECT NO: 17782

RELIABILITY MONITOR

DS80CH11 MAR '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS80CH11	A4	0103	DN029182AAA	128	LQFP	14x20x	ATK (Anam, K)
PROCESS Single Poly, Double Metal 0.6 μm PolySilicide							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

**NO OF
FAILS**

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
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PROJECT NO: 17782

RELIABILITY MONITOR

DS80CH11 JUN '01 MONITOR

DEVICE	REVISIO	DATE CD	LOT NUMBER	PINS PACKAGE	WIDTH	ASSEMBLY SITE
DS80CH11	A4	0108	DN034351AA	128 LQFP	14x20x	ATK (Anam, K)

JOB_NO	DESCRIPTION	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
27104	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
27105	STORAGE LIFE	125C	239	24	HOUR	
	MOISTURE SOAK	60C/60% R.H.	239	40	HOUR	
	CONVECTION REFLOW	235C	239	3	PASS	0
		TOTAL:				0

PROJECT NO: 18662